

PRODUCT/PROCESS CHANGE NOTICE (PCN)					
PCN #: T0403-06 DATE: 3/23/2004 Product Affected: IDT82P2288BB, IDT82P2284BB Date Effective: 6/23/2004	MEANS OF DISTINGUISHING CHANGED DEVICES: □ Product Mark □ Back Mark "ZB" prefix ■ Date Code □ Other				
Contact: Bimla Paul					
Title: Quality Assurance Manager	Attachment: Yes No				
Phone #: (408) 654-6419					
Fax #: (408) 492-8362	Samples: Available on request.				
E-mail: <u>bimla.paul@idt.com</u>					
DESCRIPTION AND PURPOSE OF CHANGE: ☐ Die Technology ☐ Wafer Fabrication Process ☐ Assembly Process ☐ Equipment ☐ Material ☐ Testing ☐ Manufacturing Site ☐ Data Sheet ☐ Other	Please see attachment for detail of change.				
RELIABILITY/QUALIFICATION SUMMARY: Please see attachment for qualification summary.					
CUSTOMER ACKNOWLEDGMENT OF RECEIPT: IDT records indicate that you require written notification of this change. Please use the acknowledgement below or E-Mail to grant approval or request additional information. If IDT does not receive acknowledgement within 30 days of this notice it will be assumed that this change is acceptable. IDT reserves the right to ship either version manufactured after the process change effective date until the inventory on the earlier version has been depleted.					
Customer:	☐ Approval for shipments prior to effective date.				
Name/Date:	E-Mail Address:				
Title:	hone# /Fax# :				
CUSTOMER COMMENTS:					
IDT ACKNOWLEDGMENT OF RECEIPT:					
RECD. BY:	DATE:				

Integrated Device Technology, Inc. 2975 Stender Way, Santa Clara, CA - 95054

PRODUCT/PROCESS CHANGE NOTICE (PCN)

ATTACHMENT - PCN #: T0403-06

PCN Type: Die Revision and datasheet change

Datasheet Change: Yes

Detail of Change: The new die revision is "ZB", and LOS status indication option for REFA_OUT and

REFB_OUT pins has been added. A register setting REFH_LOS has been added

for selecting LOS status indication. There is no change in device performance. Customers are not required to make any changes to use the new revision. Please visit the following

URL for a detailed summary of changes to the product datasheets:

IDT82P2288BB http://www1.idt.com/pcms/getDoc.taf?docID=9612
IDT82P2284BB http://www1.idt.com/pcms/getDoc.taf?docID=9616

Devices providing REFH_LOS register setting can be identified by the top mark **date code**:

Revision	Date Code Mark
Z (current)	Z yyww
ZB (new)	ZB yyww

Note: yy = last two digits of the year

ww = workweek

After the PCN effective date of 06/23/04, IDT may ship either the current revision (Z) or the new revision (ZB), unless otherwise requested.

Qualification Data

Qualification Plan: QFI-03-12R1 Test Vehicle: IDT82P2288BB

Test Description/Condition	Test Methods	Required	Qual Test Results	
	Test Methous	SS / # Fails	Lot # 1	Lot # 2
Life Test	MIL-STD-883,	77 / 0	77 / 0	77 / 0 [1]
(+125°C, 1000 hrs)	Method 1005	7770	7770	///013
Latch-Up Immunity	EIA/JESD 78	10 / 0	10 / 0	N/A
(+ - I and V stress, + - 100 mA Trigger)	EIA/JESD /6	10 / 0	10 / 0	IN/A
ESD	MIL-STD-883,	3/0	3/0	N/A
Human Body Model (2000V)	Method 3015	3/0	370	IN/A
ESD	JESD22-C101	3/0	3/0	N/A
Charge Device Model (500V)	JESD22-C101	370	370	IN/A
Highly Accelerated Stress Test (HAST)	JESD-22-A110B	45 / 0	45 / 0	N/A
(Biased, 130°C/85% RH, 100 hrs)	JLSD-22 - A110D	73/0	73/0	1 1 /A

Note:

[1] 168 hour Early Life readpoint data. 1000 hour readpoint data expected by April 30, 2004.